

PTO-1449		Application No. 09/870,144	Applicant(s) Eva M. Sevick-Muraca, et al.	
Information Disclosure Citation in an Application		Docket Number 017575.0680 (TAMUS 1685)	Group Art Unit 3768	Filing Date May 30, 2001

U.S. PATENT DOCUMENTS						
	DOCUMENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE
BK	A 5,917,190	6/29/1999	Yodh, et al.	250	458.1	7/25/1996
	B 6,480,276	11/2002	Jiang, Huabei	356	336	
	C 5,424,843	06/1995	Tromberg et al.	356	442	
	D 5,190,729	03/02/93	Hauenstein, et al.			
	E 5,736,410	04/07/98	Zarling, et al.			
	F 6,271,522	08/07/01	Lindermeir, et al.	250	341.1	05/17/99

## FOREIGN PATENT DOCUMENTS

	DOCUMENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES	NO
BK	G WO 02/41760 A2	05/30/2000	PCT	A 61 B		X	
	H GB 2311366A	03/19/1996	UK	G01N 21/49	A61B 5/00	X	
	I WO 00/22414	10/08/1999	WO	G01N	21/00	X	
	J EP 0 959 341 A1	11/24/1999	EPO	G01N	21/25		X
	K WO 99/49312	03/23/1999	PCT	G01N	33/15	X	
	L WO 01/22063 A1	09/18/2000	PCT	G01N	21/35	X	
M							
N							

	DOCUMENT (Including Author, Title, Source, and Pertinent Pages)	DATE
BK	O Sevick-Muraca, et al.; "Method and System for Detecting Sentinel Lymph Nodes;" Patent Application 10/618194; Attorney Docket Number 017575.0700; 28 pgs	July 11, 2003
	P Sevick-Muraca, et al.; "Method for Characterizing Particles in Suspension from Frequency Domain Photon Migration Measurements" Patent Application 10/115271; Attorney docket number 017575.0702; 59 pgs	April 3, 2002
	Q Sevick-Muraca, et al.; Characterizing Powders Using Frequency-Domain Photon Migration; U.S. Publication No.: 2003/0117622; Attorney docket number 017575.0701; 22 pgs 6/2003	October 21, 2002
	R Sevick-Muraca, et al.; Method for Characterizing Particles in Suspension from Frequency Domain Photon Migration Measurements; U.S. Publication No.: 2005/0073681; Attorney docket number 017575.0877; 34 pgs 4/7/2005	April 3, 2002
BK	S Sevick-Muraca, et al.; Method for Characterizing Particles in Suspension from Frequency Domain Photon Migration Measurements; Patent Application 11/204,844; Attorney Docket Number 017575.1079; 59 pgs	August 16, 2005

EXAMINER <i>Kansalhi Lay</i>	DATE CONSIDERED <i>1-23-07</i>
EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.	

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